

# Microwave Experiment: Week 3

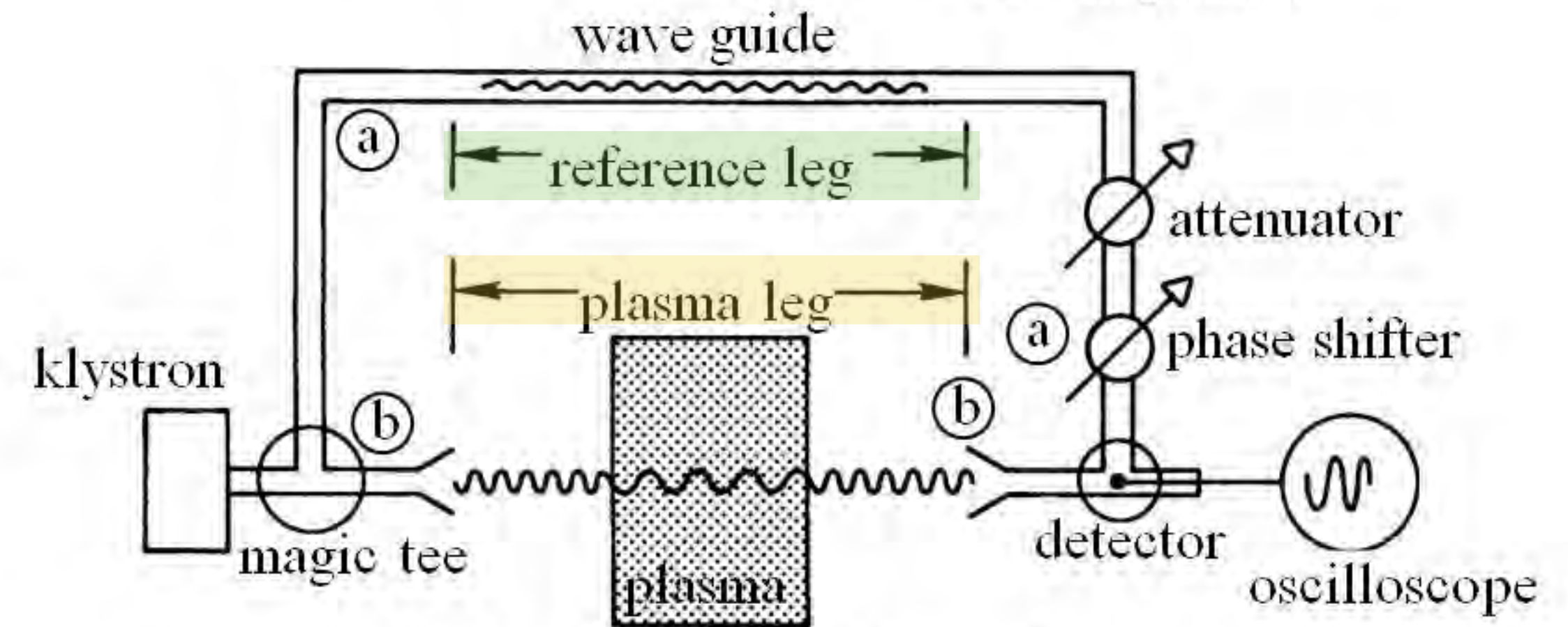
**AP 4018**  
**Columbia University**

# Objective

- Measure the complex dielectric constant of materials with a microwave interferometer

- Microwave interferometer for plasma density measurement

$$\text{index of refraction } \tilde{n} = \frac{c}{v_{ph}} = \frac{ck}{\omega} = \begin{cases} > 1 & \text{in glass} \\ = 1 & \text{in vacuum} \\ < 1 & \text{in plasma} \end{cases}$$

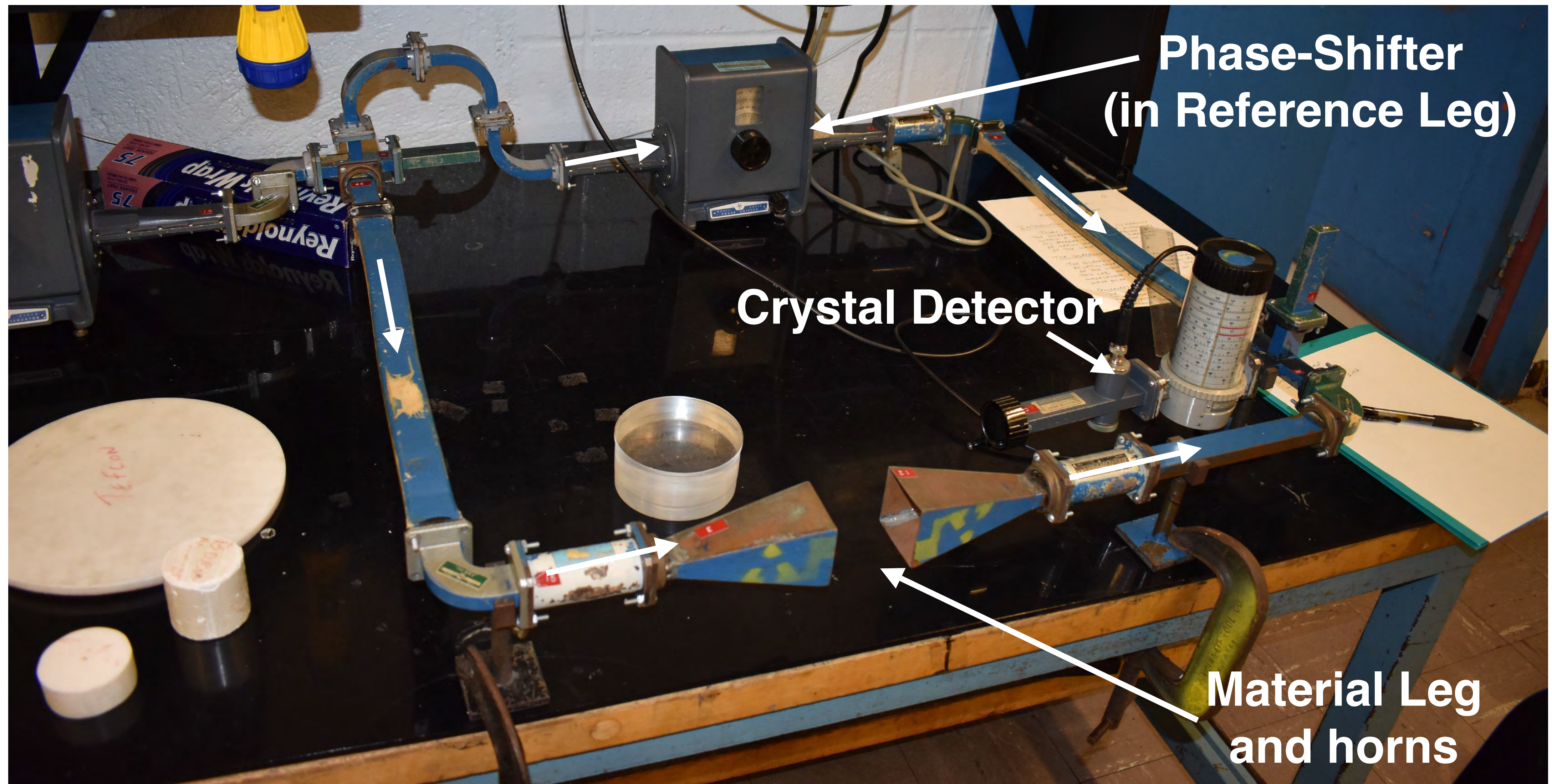


A microwave interferometer for plasma density measurement.

1. without plasma, signals from path (a) and (b) are  $180^\circ$  out of phase.
2. with plasma, the phase in (b) changed as  $\lambda f$ , (by higher plasma density).



# Components of a Microwave Interferometer



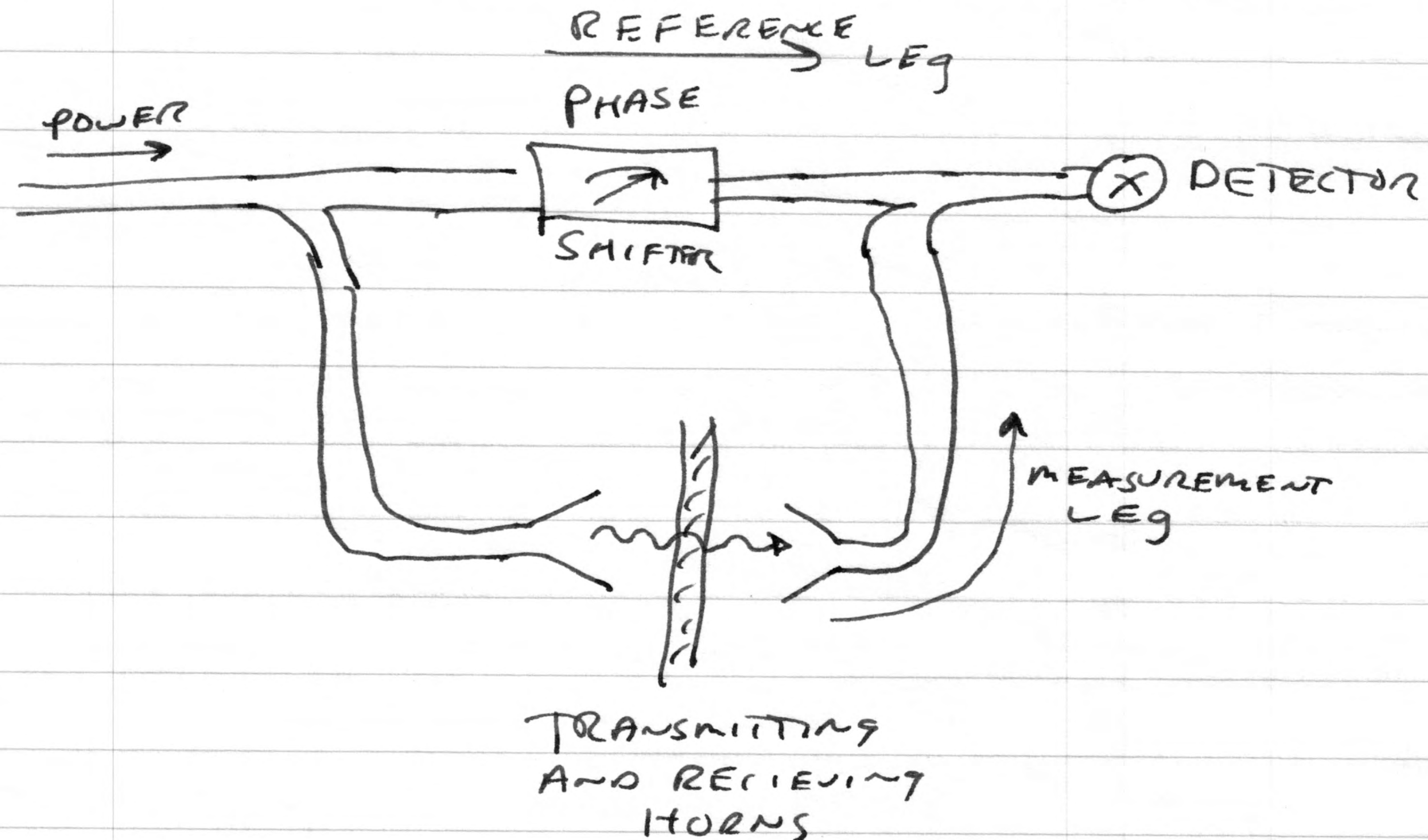


# What you can measure?

- Microwave interferometer detects the change in the wavelength and attenuation of microwaves (light) as it passes through a material *relative* to the passage through free space
- The phase changes and
- The amplitude changes

# Schematic: Diagram

THE BASIC EXPERIMENT CONSISTS OF  
THREE PARTS (PLUS THE KLYSTRON).



# Schematic: Function

1) A PHASE-SHIFTER (NOT PERFECT, BUT CLOSE)  
INSIDE THE REFERENCE LEG

2) A SQUARE-LAW DETECTOR (WHICH COMBINES  
THE SIGNALS FROM THE MEASUREMENT  
AND REFERENCE LEGS)

3) THE TRANSMITTING AND RECEIVING  
HORNS

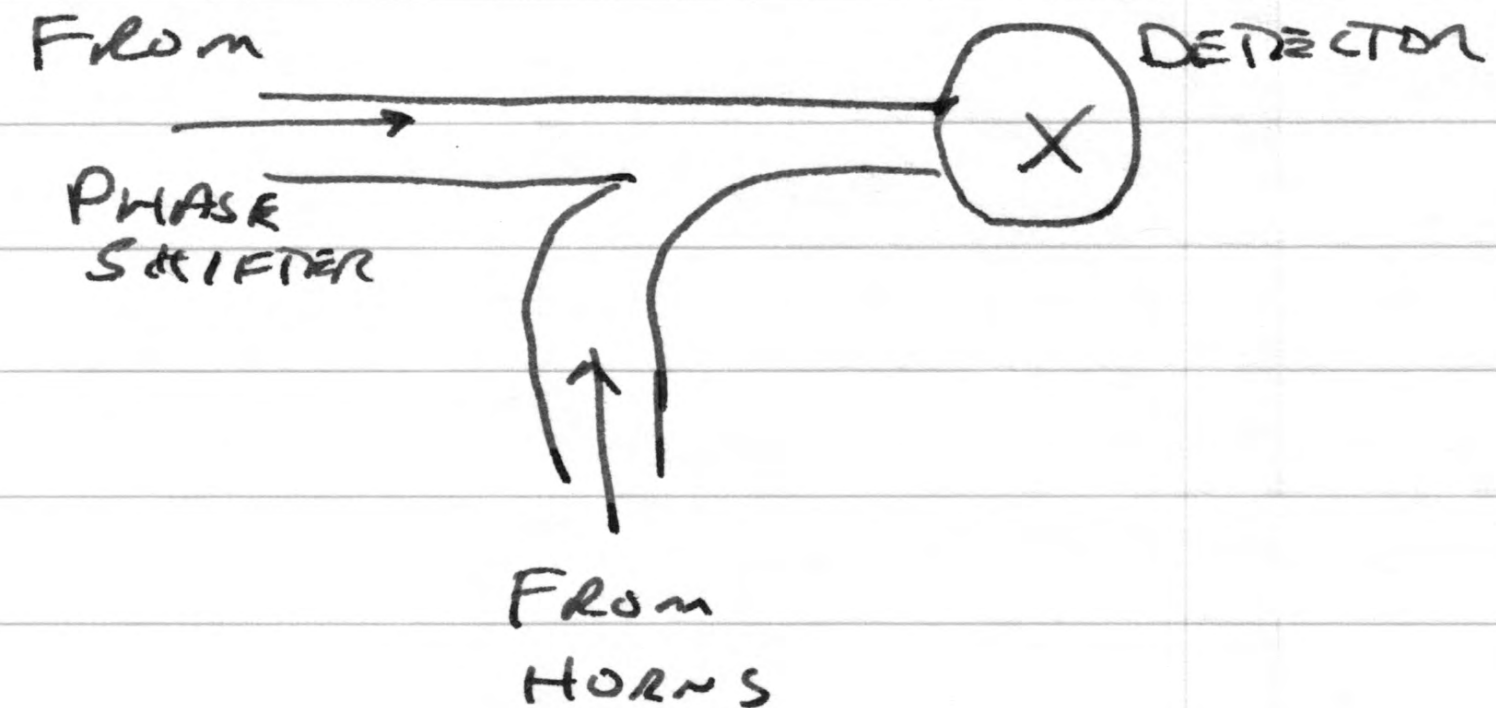
DIFFERENT MATERIALS CAN BE PLACED  
BETWEEN THE HORNS.



# Procedure

YOUR EXPERIMENTAL PROCEDURE IS USED TO MEASURE THE DIFFERENCE BETWEEN LIGHT PROPAGATION THROUGH AIR (CLOSE TO VACUUM) AND THROUGH VARIOUS MATERIALS.

WHAT HAPPENS WHEN THERE IS NOTHING PLACED BETWEEN THE HORNS?



VOLTAGE AT DETECTOR  $\propto |E|^2$

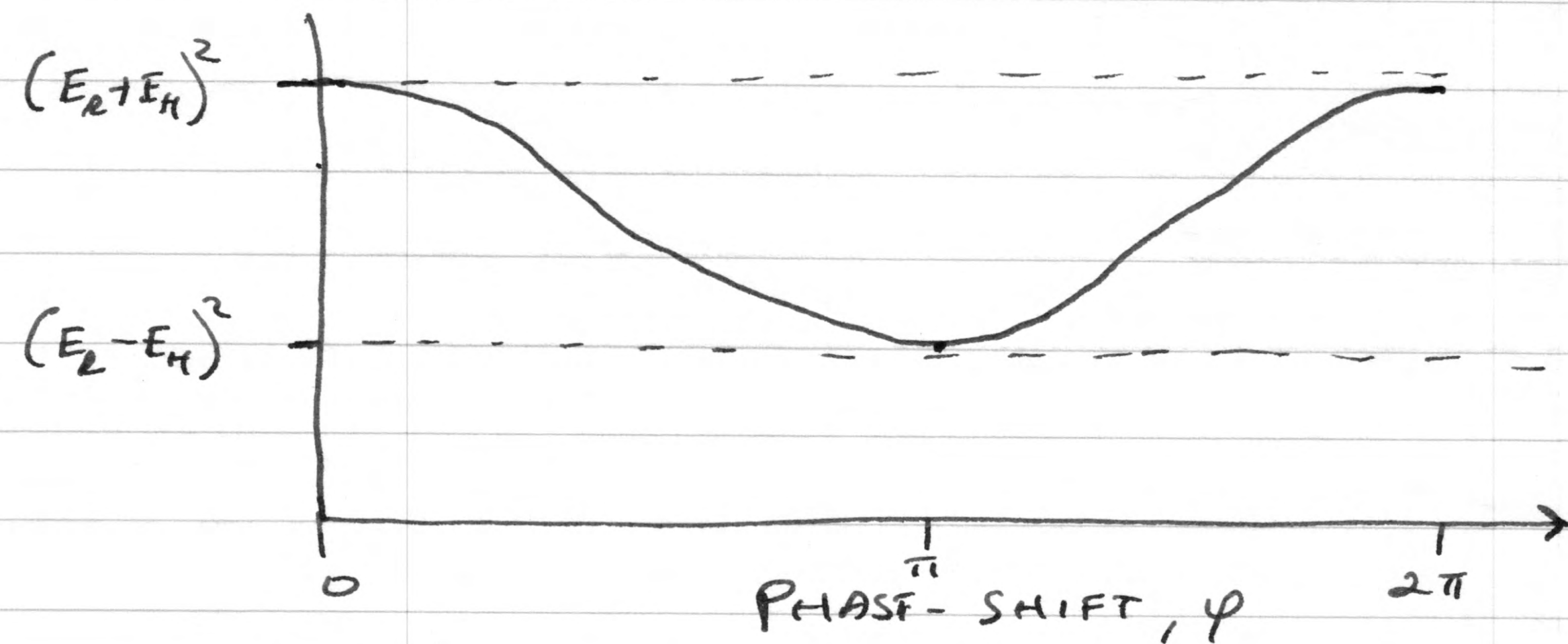
$$E = E_{REF} + E_{HORNS}$$
$$= E_R e^{-j\omega t} + E_H e^{-j\omega t + i\phi}$$

WHERE  $\phi$  IS THE PHASE DIFFERENCE BETWEEN THE SIGNAL FROM THE HORNS AND THE SIGNAL FROM THE REFERENCE!  $\phi$  CHANGES AS YOU ADJUST THE PHASE SHIFTER!!



# Procedure (continued)

$$\begin{aligned} V_{DET} &= |E_R + E_H e^{i\phi}|^2 \\ &= (E_R + E_H e^{i\phi})(E_R + E_H e^{-i\phi}) \\ &= E_R^2 + E_H^2 + E_R E_H (e^{i\phi} + e^{-i\phi}) \\ &= E_R^2 + E_H^2 + 2E_R E_H \cos(\phi) \end{aligned}$$



THUS, YOU CAN MEASURE  $V_{DET}$  VS.  $\phi$   
AND IDENTIFY

$$V_{DET \text{ MAX}} = (E_R + E_H)^2$$

$$V_{DET \text{ MIN}} = (E_R - E_H)^2$$

AND

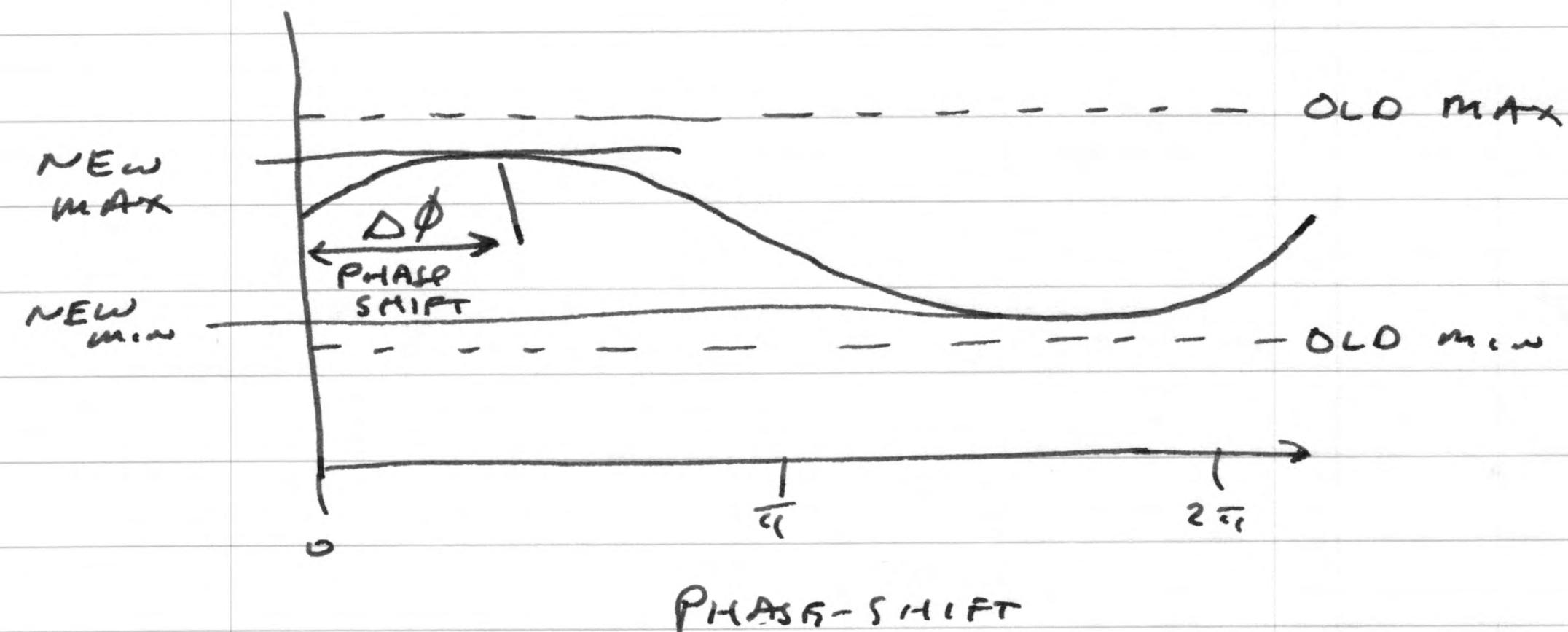
THE READINGS OF THE PHASE  
SHIFT CORRESPONDING TO  
MIN AND MAXIMUM.



# What happens when material is placed between horns?

ANSWER:

WHEN A MATERIAL IS PLACED BETWEEN THE HORNS, THE PHASE WILL CHANGE AND THE AMPLITUDE WILL CHANGE...



FROM THE NEW MIN/MAX YOU CAN CALCULATE THE ATTENUATION THROUGH THE SLAB

$$\frac{E_H'}{E_H} = e^{-\alpha d}$$

$\alpha$  = ATTENUATION COEFFICIENT  
 $d$  = THICKNESS OF SLAB

FROM THE PHASE SHIFT, YOU CAN CALCULATE THE CHANGE IN WAVELENGTH

$$\Delta\phi = (k' - k)d$$

← THICKNESS OF SLAB

$$k = \frac{2\pi}{\lambda} = \frac{2\pi}{\text{FREE-SPACE WAVELENGTH}}$$
$$k' = \frac{2\pi}{\lambda'} = \frac{2\pi}{\text{WAVELENGTH IN MATERIAL}}$$

YOU SHOULD CHECK THAT IF YOU DOUBLE THE THICKNESS OF THE MATERIAL, THEN THE ATTENUATION AND PHASE-SHIFT WILL INCREASE.



# What happens when material is placed between horns?

REMEMBER,

$$\lambda' = \sqrt{\epsilon} \lambda'$$

$$= n \lambda'$$

WHERE  $\epsilon$  = RELATIVE  
DIELECTRIC  
CONSTANT

WHERE  $n$  = INDEX OF  
REFRACTION.

NOTES THE WAVELENGTH WILL BE SMALLER

INSIDE THE MATERIAL THAN OUTSIDE.

THUS, THE SIGNAL IN THE HORNS

WILL HAVE A GREATER PHASE SHIFT

WITH A MATERIAL THAN WITHOUT MATERIAL.



# What is Contained in Data File?

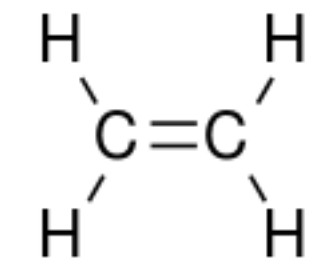
Microwave-Week-3-Data.csv

- Measured @ frequency = 9.430 GHz
- Recorded the phase of *minimum* and *maximum* electric field intensity
- Recorded the magnitude of the *minimum* and *maximum* (as  $V_{\text{det}} \propto |E_r + E_m|^2$ )

- ***For the following cases:***

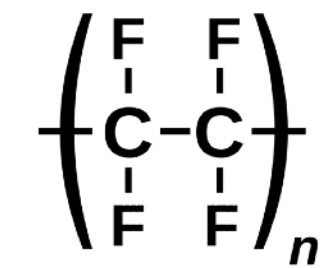
- Air

- 3 cm thick Polyethene

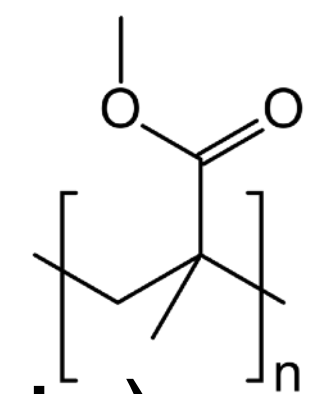


- 2 cm thick Teflon

- 0.9 cm thick Teflon



- 4.5 cm thick Lucite  
(or Poly(methyl methacrylate))





# Summary: Week 3

- Measure the propagation of microwaves through materials using a microwave interferometer.